

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM  
10079389

FILING DATE  
02/20/2002

CLASS  
356

SUBCLASS  
189

GAU  
2877

EXAMINER  
*Wachman*

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\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

PG-PUB  DO NOT PUBLISH

RESCIND

Foreign priority claimed

yes  no

35 USC 119 conditions met

yes  no

Verified and Acknowledged Examiners's initials *HJZ*

ATTORNEY DOCKET NO

BUR920010128US1 (15015)

TITLE : Contact hole profile and line edge width metrology for critical image control and feedback of lithographic focus

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED

Assistant Examiner

CLAIMS ALLOWED

Total Claims

Print Claim for O.G

ISSUE FEE

Amount Due  Date Paid

DRAWING

Sheets Drwg.

Figs.Drwg.

Print Fig.

TERMINAL

DISCLAIMER

Primary Examiner

PREPARED FOR ISSUE

Application Examiner

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FILED WITH:

DISK (CRF)

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